

CITY OF NEW YORK  
DEPARTMENT OF BUILDINGS

Pursuant to Administrative Code Section 27-131, the following equipment or material has been found acceptable for use in accordance with the Report of Materials and Equipment Acceptance (MEA) Division.

Richard C. Visconti, R.A., Acting Commissioner  
MEA 211-00-E

Report of Material and Equipment Acceptance Division

Manufacturer - Systems Sensor, A Division of Pittway, 3825 Stern Avenue,  
St. Charles, IL. 60174

Trade Name(s) - System Sensor.

Product - Fire Alarm Equipment.

Pertinent Code Section(s) - Reference Standard RS 17-3, RS 4-6 (886-89-BCR).

Test(s) - UL 864.

Laboratory - Underwriters Laboratories, Inc.

Test Report(s) - UL File S911, Project 94NK18295, Volume 12, Section 4, Issued  
December 5, 1994, revised April 14, 2000 and UL letter dated May 25, 2000.

Description - System Sensor's smoke detector as follows:

Model Number	Description
B501B-FTX	Smoke Detector base for use with Filtrex Smoke Detector 15 to 32 VDC

Pursuant to "Promulgation of the Rules relating to Material and Equipment Application Procedures" dated November 5, 1992, the Bureau of Fire Prevention has no objections letter dated July 13, 2000, F.P. Index No. 0006020.

Recommendation - That the above unit, be accepted on conditions that all uses, configurations, arrangements, functions, applications, and installations shall comply with the provisions of New York City Building Code, specifically Subchapter 17, and Reference Standards RS 17-11 & 17-12. Further, the installation shall be in accordance with the manufacturer's recommendation, NFPA 72 and the UL Standard. This detector base shall be utilized only with listed and approved detecting devices which the compatibility has been determined by a UL test report.

All shipments and deliveries of such equipment shall be provided with a metal tag, suitably placed, certifying that the equipment shipped or delivered is equivalent to those tested and accepted for use, as provided for in Section 27-131 of the Building Code.

Final Acceptance November 17, 2000  
Examined By Mark Jech